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PATENT APPLICATION
Docket No.: 301500.3000-106

UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Oleg P. Kishkovich, Anatoly Grayfer, William M. Goodwin and
Devon Kinkead

Application No.: 10/662,892 Filed Date: September 15, 2003

Confirmation No. 1170 Group: 2812 Examiner: Not Assigned

For: System and Method for Monitoring Contamination

CERTIFICATE OF MAILING	
I Hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450	
on <u>May 17, 2004</u>	<u>Mary P. McDermott</u>
Date	Signature
<u>MARY P. McDERMOTT</u>	
Typed or printed name of person signing certificate	

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This Information Disclosure Statement is submitted:

- ☐ under 37 CFR 1.129(a), or
(First/Second submission after Final Rejection)
- ☒ under 37 CFR 1.97(b), or
(Within any one of the following time periods: three months of filing national application (other than a CPA) or date of entry of the national stage in an international application; or before the mailing date of a first office action on the merits in a non-provisional application, including a CPA, or a Request for Continued Examination).
- ☐ under 37 CFR 1.97(c) together with either:
☐ a Statement under 37 CFR 1.97(e), as checked below, or
☐ a \$180.00 fee under 37 CFR 1.17(p), or
(More than 3 months after receipt of the International Search Report, but before final action or notice of allowance, whichever occurs first)
- ☐ under 37 CFR 1.97(d) together with:
☐ a Statement under 37 CFR 1.97(e), as checked below, and
☐ a \$180.00 fee under 37 CFR 1.17(p), or
(Filed after final action or notice of allowance, whichever occurs first, but on or before payment of the issue fee)
- ☐ under 37 CFR 1.97(i):
Applicant requests that the IDS and cited reference(s) be placed in the application filewrapper.
(Filed after payment of issue fee)

Statement Under 37 CFR 1.97(e)

- ☐ Each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement; or
- ☐ No item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the undersigned, after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in 37 CFR 1.56(c) more than three months prior to the filing of this Information Disclosure Statement.

Statement Under 37 CFR 1.704(d) (Patent Term Adjustment)

Applies to original applications (other than design) filed on or after May 29, 2000

- ☐ Each item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart application and this communication was not received by any individual designated in § 1.56(c) more than thirty days prior to the filing of the Information Disclosure Statement.

Enclosed herewith is form PTO-1449:

- ☒ Copies of the cited references (AO2, and AR-AT) are enclosed.
- ☒ In accordance with 37 C.F.R. § 1.98 (d), copies of cited references (AA-AK, AA2-AC2, AL-AQ and AL2-AN2) are not enclosed as these references were entered in earlier application, U.S. Application No. 09/961,802, now Patent No. 6,620,630 to which the present application claims priority under 35 U.S.C. 120. The earlier application contains copies of the cited references.
- ☒ If copies of references (AA-AK, AA2-AC2, AL-AQ and AL2-AN2) would benefit the Examiner of this case, the Examiner is invited to call the undersigned attorney and copies will be forwarded immediately.
- ☒ Listed references [AH-AK, AA2-AB2 and AL2-AN2] were cited in the enclosed International Search Report in a counterpart foreign application.

Concise Explanation Requirement (non-English references):

- ☐ The "concise explanation" requirement (non-English references) for reference(s) [] under 37 CFR 1.98(a)(3) is satisfied by:
 - ☐ the explanation provided on the attached sheet.
 - ☐ the explanation provided in the Specification.
 - ☐ submission of the enclosed International Search Report.
 - ☐ the enclosed English language abstract.

☐ Applicant requests that the following pending applications be considered:

Examiner's
Initials

____ U.S. Patent Application No. [], Publication No. [], Publication Date [],
by [inventor(s)], filed [], Docket No.: []

____ U.S. Patent Application No. [], Publication No. [], Publication Date [],
by [inventor(s)], filed [], Docket No.: []

____ U.S. Patent Application No. [], Publication No. [], Publication Date [],
by [inventor(s)], filed [], Docket No.: []

Examiner

Date

- ☐ A copy of each above-cited application, including the current claims, is enclosed.
- ☐ A copy of each above-cited application, including the current claims, is enclosed, except those entered in prior application, U.S. Application No. [], to which priority under 35 U.S.C. 120 is claimed.

The Examiner is requested to return a copy of the above list of pending applications indicating which references were considered with the next office communication.

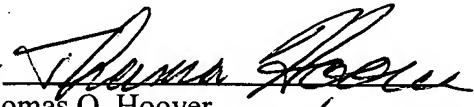
It is requested that the information disclosed herein be made of record in this application.

Method of payment:

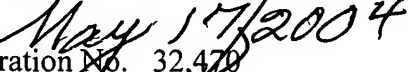
- ☐ A check for the fee noted above is enclosed, or the fee has been included in the check with the accompanying Reply. A copy of this Statement is enclosed.
- ☐ Please charge Deposit Account No. 50-1935 in the amount of \$[]. A copy of this Statement is enclosed.
- ☒ Please charge any deficiency in fees and credit any overpayment to Deposit Account No. 50-1935.

Respectfully submitted,

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3510-1449 REPRODUCTION OF INFORMATION DISCLOSURE CITATION IN AN APPLICATION 5/17/2004 (Use several sheets if necessary)	ATTORNEY DOCKET NO. 301500.3000-106	APPLICATION NO. 10/662,892
	APPLICANT Oleg P. Kishkovich <i>et al.</i>	
	FILING DATE September 15, 2003	GROUP ART UNIT 2812

U.S. PATENT DOCUMENTS

EXAM- -INER INI- TIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	AA	3,834,122	Sep 10 1974	Allison et al.	55	33	
	AB	4,170,901	Oct 16 1979	Conkle et al.	73	421.5	
	AC	4,429,736	Feb 07 1984	Turner	165	61	
	AD	4,645,516	Feb 24 1987	Doshi	55	16	
	AE	5,122,355	Jun 16 1992	Prasad et al.	423	351	
	AF	5,574,230	Nov 12 1996	Baugh	73	863.23	
	AG	5,773,713	Jun 30 1998	Barber et al.	73	61.41	
	AH	4,998,433	Mar 12 1991	Stumpf et al.	73	25.01	
	AI	5,856,198	Jan 5 1999	Joffe et al.	436	100	
	AJ	5,983,704	Nov 16 1999	Park et al.	73	28.01	
	AK	6,096,267	Aug 1 2000	Kishkovich et al.	422	52	
	AA2	6,287,023	Sep 11 2001	Yaegashi et al.	396	565	
	AB2	6,290,779	Sep 18 2001	Saleh et al.	134	2	
	AC2	5,274,434	Dec 28 1993	Morioka et al.	356	237	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES	NO
	AL	DE 198 47 697	20 Apr 2000	Denmark (English Abstract)				
	AM	EP 0 692 297	17 Jan 1996	EPO				
	AN	EP 1 166 845	27 Jun 2001	EPO				
	AO	JP 11-57346	02 Mar 1999	Japan (English Abstract)				
	AP	JP 11-64316	05 Mar 1999	Japan (English Abstract)				
	AQ	JP 11-20034	26 Jan 1999	Japan (English Abstract)				
	AL2	DE 198 41 814	16 MAR 2000	Denmark				X
	AM2	EP 0 298 000	04 Jan 1989	EPO				
	AN2	EP 1 190 945	27 Mar 2002	EPO				

EXAMINER	DATE CONSIDERED
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PTO-1449 REPRODUCED INFORMATION DISCLOSURE CITATION IN AN APPLICATION 5/17/2004 (Use several sheets if necessary)				ATTORNEY DOCKET NO. 301500.3000-106		APPLICATION NO. 10/662,892	
				APPLICANT Oleg P. Kishkovich <i>et al.</i>			
				FILING DATE September 15, 2003		GROUP ART UNIT 2812	
U.S. PATENT DOCUMENTS							
EXAM- INER INI- TIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	AD2	4,474,051	Oct 2 1984	Fukuda et al.	73	19	
	AE2	5,054,046	Oct 1 1991	Shoulders	378	119	
	AF2	5,153,901	Oct 6 1992	Shoulders	378	119	
	AG2	5,168,068	Dec 1 1992	Yanagisawa et al.	436	134	
	AH2	6,168,948	Jan 2 2001	Anderson et al.	435	287.2	
	AI2	5,481,110	Jan 2 1996	Krishnaswamy et al.	250	288	
	AJ2	5,725,634	Mar 10 1998	Takasuga et al.	95	45	
	AK2	5,841,022	Nov 24 1998	Hase	73	23.22	
	AA3	5,898,114	Apr 27 1999	Basch et al.	73	863.23	
	AB3	5,935,302	Aug 10 1999	Ju et al.	95	4	
	AC3	6,009,739	Jan 4 2000	Fujiwara et al.	73	1.02	
	AD3	6,119,532	Sep 19 2000	Park et al.	73	864.34	
	AE3	6,139,801	Oct 31 2000	Kawachi et al.	422	88	
	AF3	6,239,038	May 29 2001	Wen	438	745	
	AC3	6,295,864	Oct 2 2001	You et al.	73	53.01	
	AH3	6,310,356	Oct 30 2001	Yuhara et al.	250	574	
	AI3	6,467,333	Oct 22 2002	Lewis et al.	73	31.05	
	AJ3	6,470,760	Oct 29 2002	Shinozaki et al.	73	863.33	
	AK3	6,497,136	Dec 24 2002	Satou	73	23.22	
	AA4	6,620,630	Sep 16 2003	Kishkovish et al.	438	7	
	AB4	2002/0121148 A1	Sep 5 2002	Shinozaki et al.	73	863.33	Jun 29 1999
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO
	AO2	2 320 088	10 Jun 1998	UK patent application			
EXAMINER				DATE CONSIDERED			

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		APPLICANT Oleg P. Kishkovich <i>et al.</i>	
		FILING DATE September 15, 2003	GROUP ART UNIT 2812
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)			
	AR	Ogawa & Company, company website, www.ogawausa.com, About Ogawa & Company, July 24, 2003.	
	AS	Ogawa & Company, company website, www.ogawausa.com, Passive Sampler, July 24, 2003.	
	AT	Dallas, et al., "Characterization and Control of Organic Airborne Contamination in Lithographic Processing", Paper presented at SPIE Microlithography 2002.	
EXAMINER		DATE CONSIDERED	